IMPROVE YOUR SCIENCE WITH THE ALL-NEW

AXRD® THETA/THETA POWDER DIFFRACTOMETER



ADVANCED SYSTEM FUNCTIONALITY IN A COMPACT FOOTPRINT

- 200 mm Goniometer Radius
- –1200 Watt X-ray System
- High-Speed Photon Counting Detector
- 1200°C Temperature Stage Option
- Gas Pressure Stage Option
- Compact Footprint (H x W x D) 67.5" x 37.6" x 24"



PROTO

www.protoxrd.com





PROTO Manufacturing Inc. 12350 Universal Dr. Taylor, Michigan Made in USA USA, 48180-4070

Agent: Hanmi Tech Co 02-2226-2421 www.nayur.kr

PROTO AXRD θ-θ Diffractometer

The AXRD θ - θ diffractometer is easy to use and provides accurate and reliable measurements, with comparable speed to full size laboratory units. This unit combines the best qualities of lab systems and benchtop systems into one. The AXRD θ - θ has the reduced footprint and easy maintenance of a benchtop and the seemingly infinite versatility and higher power of a traditional lab unit – without the noisy and bulky external chiller. Equipped with either our high-speed linear hybrid photon counting detector or our energydiscriminating silicon point detector (SPD), the AXRD θ - θ has fast data collection capabilities while maintaining research-quality standards. With an achievable FWHM peak resolution of $< 0.05^{\circ}$ 20 and an angular accuracy of $< \pm 0.02^{\circ} \Delta 2\theta$ over the full angular range, the AXRD θ - θ provides the necessary level of performance for even the most demanding x-ray diffraction material investigation.

The AXRD θ - θ has everything you need for phase identification, quantitative phase analysis, percent crystallinity, crystallite size and strain, Rietveld refinement, characterization of films and thin coatings, and structure analysis. With multiple sample stages and holders, powerful software and database options, the AXRD θ - θ provides the versatility you need for your measurements.







em	Specifications	
1	AXRD [®] θ-θ Powder Diffractometer	
	High-accuracy powder diffraction and reliability in a benchtop configuration. 600 Watts	
	and independent θ and 2θ axes enable more flexibility in diffraction experiments.	
	Geometries Included	
	Bragg-Brentano vertical parafocusing θ/θ with horizontal sample orientation.	
	Rocking curves and residual stress analysis	
	Glancing-incidence for film and coating analysis	
	Goniometer Radius	
	200 mm	
	Max. useable angular range	
	-4 to 150° 2θ	
	Scanning Speed	
	0.0001° to 100°/min (2θ)	
	Max Motor Speed (Slew)	
	1000°/min	
	Motor Step Resolution	
	0.0003°	
	Accuracy	
	± 0.02° 2θ	
	Slits (universal slit size for all positions)	
	Divergence: 4 fixed included (options (mm): 0.04, 0.1, 0.2, 0.3, 0.4, 0.5, 1.0, 2.0)	
	Soller: Incident and diffracted beam (high-resolution or high-speed)	
	Anti-scatter: 1 fixed (point detectors only)	
	Receiving Slit: 3 fixed included (point detectors only; see size options above)	
	Achievable peak width	
	< 0.05° 20	
	X-ray Tube (Cu, Co, Cr, Mo and Custom Tubes Available)	
	Fine focus Cu-anode metal/ceramic construction 1500-Watt x-ray tube (Manufactured by	
	PROTO)	
	X-ray Power	
	1,200 Watts (40 kV/30 mA)	
	10-40 kV in steps of 0.1 kV	
	0-30 mA in steps of 0.1 mA	
	\leq 0.01% HV output for change in main of ± 30%	
	Safety key to enable and disable x-ray generation	
	Regulation features include: arc suppression, over voltage, over current and over power	
	Automated tube warm-up, tube ramping	
	X-ray tube cooling	
	Internal water cooling radiator and tank	
	Detector	
	PROTO [®] Silicon Point Detector (SPD) (digital monochromator; qualitative XRF)	

	Exterior Dimension	
	171 x 61 x 100 cm (h x d x w), 67.5" x 24" x 37.6"	
	Weight	
	200 kg (440 lbs)	
	AC Input Power	
	208 VAC, 50/60 Hz, 10 A, Single Phase	
	Computer	
	Desktop PC with Windows 10	
	Interface	
	Ethernet	
	Software	
	XRDWIN PD Measurement Software	
	Instrument warm-up and control, data collection	
	PD Analysis Software	
	Peak search, fitting, and profile analysis	
	Background fitting (manual and automatic)	
	Data smoothing and $K_{\alpha 2}$ stripping	
	Intensity ratio method for quantitative analysis	
	Spike method for quantitative analysis	
	Search-Match for Crystallography Open Database and/or ICDD (if purchased)	
	Lattice parameter refinement and indexing	
	Residual stress, free lime, crystallinity, crystallite size, and other analysis techniques	
	Standards and Safety	
	Compliant with: UL/CSA, CE, ANSI N43.2	
	Interlocked enclosure door for auto x-ray off	
	Sample Holders (Amorphous Polymer: single-sample stage) 6 holders total	
	3 Double-sided sample holder shallow (13 and 26 mm diameter cavity; 0.5 mm depth)	
	3 Deep sample cups (38 mm diameter; 10 mm depth)	
	Reference Sample	
	LaB ₆ powder disc	
	Databases Included	
2	Crystallography Open Database (Over 300,000 structures for Search-Match & Rietveld)	
3	American Mineralogist Crystal Structure Database (19,727 entries for Search-Match &	
	Rietveld)	
	Warranty and Install	
4	Year 1: Complete System Warranty (x-ray tube, parts, and labor)	
5	Install and training: 3 days total (includes training with a PROTO XRD scientist)	